

**Amendments to the Claims:**

This listing of claims will replace all prior versions, and listings of claims in the application:

**Listing of Claims:**

Claims 1-13 (withdrawn).

Claim 14 (original): A method of inspecting particles or defects comprising the steps of:

    irradiating an object under inspection with light;  
    detecting reflected light or scattered light from the object under inspection;  
    detecting particles or defects based on a signal indicative of detected reflected light or scattered light;

    processing the signal indicative of detected reflected light or scattered light to measure a size of each particle or defect;

    processing data including the signal indicative of detected reflected light or scattered light, and a result of measuring the size of each particle or defect; and

    displaying the result of data processing,  
    wherein said step of processing data includes dividing the object under inspection into several regions, and processing data for each of the regions.

Claim 15 (original): A method of inspecting particles or defects according to claim 14, wherein said step of displaying includes displaying particles or defects having a particular size in a manner discriminative from the remaining particles or defects for each of the regions.

Claim 16 (original): A method of inspecting particles or defects according to claim 14, wherein said step of displaying includes displaying a distribution of frequencies for the particle or defect sizes in each of the regions.

Claims 17-20 (withdrawn).

PATENT

Claim 21 (New): A method as in claim 14 further comprising displaying a distribution of frequencies for particle or defect sizes measured.

Claim 22 (New): A method as in claim 14 further comprising displaying particles or defects having a particular size in a manner to discriminate particles or defects of that particular size from particles or defects of other sizes.